

DEPARTMENT OF MATERIALS SCIENCE AND TECHOLOGY **COURSE SYLLABUS**

Course Details										
Code					Academic Year			Semester		
MWT408				3		6				
Title					Т	Α	L	ECTS		
Advanced Characterization Techniques of Materials					2	1	1	6		
Language	German									
Level	Undergraduate X Graduate					Postgraduate				
Department / Program	Materials Science a	Materials Science and Technology								
Forms of Teaching and Learning	Face to face									
Course Type	Compulsory					Ele	ctive			х
Objectives	The students learn develop the unde appropriate mater structure and prop	The students learn the fundamentals of advanced materials characterization methods. They develop the understanding of determining proper characterization method according to appropriate materials. These methods are used to understand the relationship between structure and properties, as well as surface properties and performance of the materials.								
Content	X-ray diffraction; Investigation of crystal structure, phase analysis and elemental analysis, fundamentals of electron microscopy; Scanning Electron Microscope (SEM), Transmission Electron Microscopy (TEM), Diffraction Pattern, Sample Preparation for TEM, X-ray Photoelectron Spectroscopy (XPS), Auger Electron Microscopy (AES), Secondary Ion Mass Spectrometry (SIMS), Atomic Force Microscopy (AFM), Scanning Tunneling Microscopy (STM)									
Prerequisites										
Coordinator										
Lecturer(s)	Asist. Prof.Dr. Duy	Asist. Prof.Dr. Duygu Ekinci								
Assistant(s)										
Work Placement	No									
Recommended or Required R	eading									
Books / Lecture Notes	C.Kittel: "Einführung in die Festkörperphysik", Oldenbourg-Verlag (2006); C. Kittel, "Introduction to Solid State Physics", Wiley, New York (2005)									
Other Sources										
Additional Course Material										
Documents										
Assignments										
Exams										
Course Composition										
Mathematics und Basic Sciences									%	



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Engineering		100%					
Engineering Design		%					
Social Sciences		%					
Educational Sciences		%					
Natural Sciences		%					
Health Sciences		%					
Expert Knowledge		%					
Assessment							
Activity	Count	Percentage (%)					
Activity Midterm Exam	Count 1	Percentage (%) 40					
Activity Midterm Exam Quiz	Count 1	Percentage (%) 40					
Activity Midterm Exam Quiz Assignments	Count 1	Percentage (%) 40					
Activity Midterm Exam Quiz Assignments Attendance	Count 1	Percentage (%) 40					
Activity Midterm Exam Quiz Assignments Attendance Recitations	Count 1	Percentage (%) 40					
Activity Midterm Exam Quiz Assignments Attendance Recitations Projects	Count 1	Percentage (%) 40					
Activity Midterm Exam Quiz Assignments Attendance Recitations Projects Final Exam	Count 1 1	Percentage (%) 40 60					

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ECTS	Points	and	Work	Load

Activity	Count	Duration	Work Load (Hours)
Lectures	15	2	30
Self-Study	10	10	100
Assignments			
Presentation / Seminar Preparation			
Midterm Exam	1	2	2
Recitations	15	1	1
Laboratory	15	2	30
Projects			
Final Exam	1	2	2
		Total Work Load	179
	6		

Learning Outcomes

1	The students learn the fundamentals of advanced materials characterization methods.
2	
3	
4	
5	



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6									
7									
8									
9									
10									
11									
12									
Weekly Conter	nt								
1	Metallographic	c study of the tra	ansformation be	ehavior of steel					
2	Preparation an	id characterizati	on of CdTe thin	-film solar cells					
3									
4									
5									
6									
7									
8									
9									
10									
11									
12									
13									
14									
15									
Contribution of Learning Outcomes to Program Objectives (1-5)									
	P1	P2	P3	P4	P5	P6	P7		
All		2	3						
1									
2									
3									
4									
5									
7									
8									
9									



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10								
11								
12								
Contribution Level 1: Low 2: Low-intermediate 3: Intermediate 4: High 5: Very High								
Compiled by								
Date of Compilation:								